



ALPHA & OMEGA
SEMICONDUCTOR



AO6706

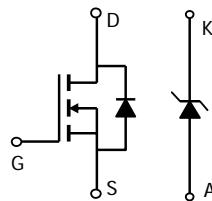
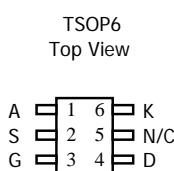
N-Channel Enhancement Mode Field Effect Transistor with Schottky Diode

General Description

The AO6706 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. A Schottky diode is provided to facilitate the implementation of a bidirectional blocking switch, or for DC-DC conversion applications. Standard Product AO6706 is Pb-free (meets ROHS & Sony 259 specifications). AO6706L is a Green Product ordering option. AO6706 and AO6706L are electrically identical.

Features

V_{DS} (V) = 30V
 I_D = 3.6A (V_{GS} = 10V)
 $R_{DS(ON)} < 65m\Omega$ (V_{GS} = 10V)
 $R_{DS(ON)} < 75m\Omega$ (V_{GS} = 4.5V)
 $R_{DS(ON)} < 160m\Omega$ (V_{GS} = 2.5V)
SCHOTTKY
 V_{DS} (V) = 20V, I_F = 1A, $V_F < 0.5V @ 0.5A$



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	MOSFET	Schottky	Units
Drain-Source Voltage	V_{DS}	30		V
Gate-Source Voltage	V_{GS}	± 12		V
Continuous Drain Current ^A	I_D	3.3		A
		2.6		
Pulsed Drain Current ^B	I_{DM}	10		
Schottky reverse voltage	V_{KA}		20	V
Continuous Forward Current ^A	I_F		2	A
			1	
Pulsed Forward Current ^B	I_{FM}		10	
Power Dissipation	P_D	1.15	0.92	W
		0.7	0.59	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	°C

Parameter: Thermal Characteristics MOSFET	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	80.3	110	°C/W
Maximum Junction-to-Ambient ^A		117	150	
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	43	80	
Thermal Characteristics Schottky				
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	109.4	135	°C/W
Maximum Junction-to-Ambient ^A		136.5	175	
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	58.5	80	

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm12\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.4	1.8	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	10			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=3.3\text{A}$ $T_J=125^\circ\text{C}$		44	65	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3.0\text{A}$		53	75	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=1\text{A}$		106	160	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=3.3\text{A}$		11.7		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.81	1	V
I_S	Maximum Body-Diode Continuous Current				2.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		226	270	pF
C_{oss}	Output Capacitance			39		pF
C_{rss}	Reverse Transfer Capacitance			29		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.4	1.7	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=3.3\text{A}$		3	3.6	nC
Q_{gs}	Gate Source Charge			1.4		nC
Q_{gd}	Gate Drain Charge			0.55		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=4.7\Omega, R_{\text{GEN}}=6\Omega$		2.6		ns
t_r	Turn-On Rise Time			3.2		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			14.5		ns
t_f	Turn-Off Fall Time			2.1		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.3\text{A}, dI/dt=100\text{A}/\mu\text{s}$		10.2	13	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.3\text{A}, dI/dt=100\text{A}/\mu\text{s}$		3.8		nC
SCHOTTKY PARAMETERS						
V_F	Forward Voltage Drop	$I_F=0.5\text{A}$		0.39	0.5	V
I_{rm}	Maximum reverse leakage current	$V_R=16\text{V}$			0.1	mA
		$V_R=16\text{V}, T_J=125^\circ\text{C}$			20	
C_T	Junction Capacitance	$V_R=10\text{V}$		34		pF
t_{rr}	Schottky Reverse Recovery Time	$I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$		5.2	10	ns
Q_{rr}	Schottky Reverse Recovery Charge	$I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$		0.8		nC

A: The value of $R_{\text{on,JA}}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The $R_{\text{on,JA}}$ is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

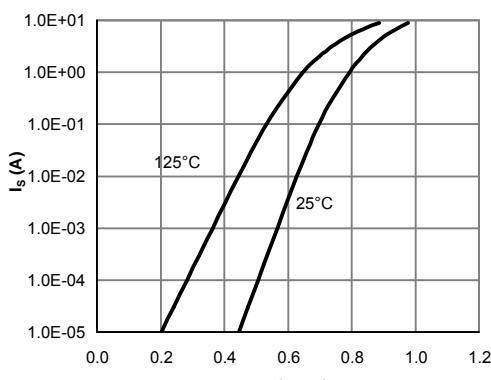
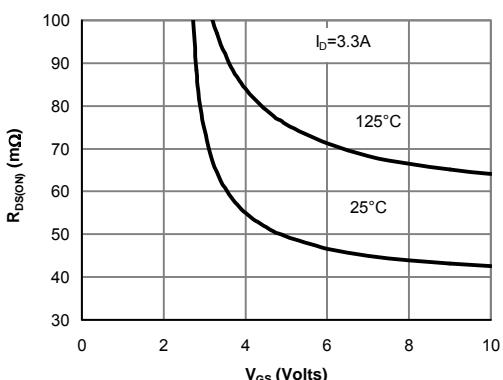
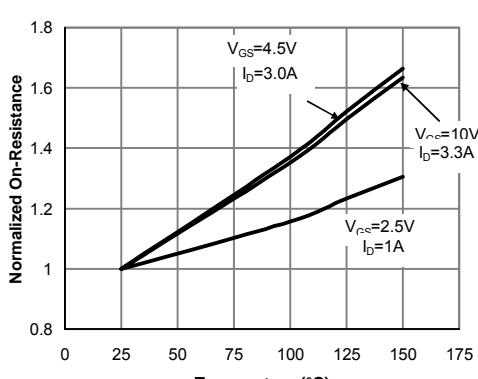
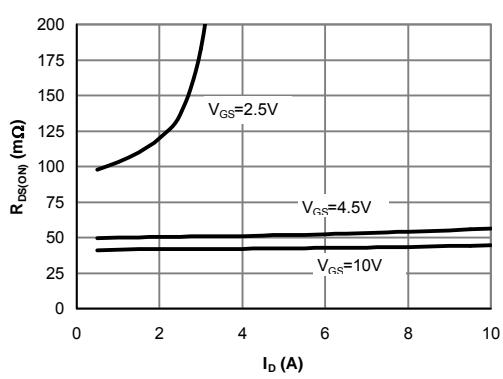
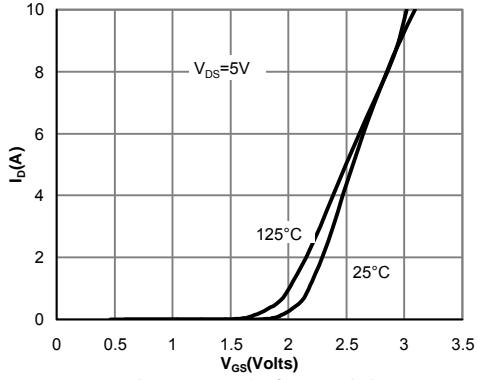
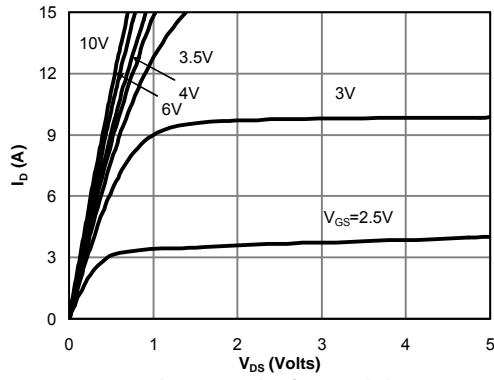
D: The static characteristics in Figures 1 to 6 are obtained using 80 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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